# **Power MOSFET** 60 V, 8.9 m $\Omega$ , 49 A, Single N–Channel

#### Features

- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Q<sub>G</sub> and Capacitance to Minimize Driver Losses
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

MAXIMUM RATINGS (	T <sub>J</sub> = 25°C	unless otherw	/ise noted)		
Param	Parameter			Value	Unit
Drain-to-Source Voltage			V <sub>DSS</sub>	60	V
Gate-to-Source Voltage			V <sub>GS</sub>	±20	V
Continuous Drain Cur-		$T_{C} = 25^{\circ}C$	I <sub>D</sub>	49	А
rent $R_{\theta JC}$ (Notes 1 & 3)	Steady	$T_{C} = 100^{\circ}C$		34	
Power Dissipation $R_{\theta JC}$	State	$T_{\rm C} = 25^{\circ}{\rm C}$	PD	44	W
(Note 1)		$T_{C} = 100^{\circ}C$		22	1
Continuous Drain	Steady State	$T_A = 25^{\circ}C$	Ι <sub>D</sub>	13	А
Current R <sub>θJA</sub> (Notes 1, 2 & 3)		$T_A = 100^{\circ}C$		9.0	1
Power Dissipation $R_{\theta JA}$		T <sub>A</sub> = 25°C	PD	3.1	W
(Notes 1 & 2)		$T_A = 100^{\circ}C$		1.5	1
Pulsed Drain Current	T <sub>A</sub> = 25°	C, t <sub>p</sub> = 10 μs	I <sub>DM</sub>	250	А
Operating Junction and Storage Temperature			T <sub>J</sub> , T <sub>stg</sub>	-55 to 175	°C
Source Current (Body Diode)			IS	25	Α
Single Pulse Drain-to-Source Avalanche Energy (T <sub>J</sub> = 25°C, $I_{L(pk)}$ = 3 A)			E <sub>AS</sub>	104	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			ΤL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

#### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain) (Note 1)	$R_{\theta JC}$	3.4	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	48.7	

1. The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.

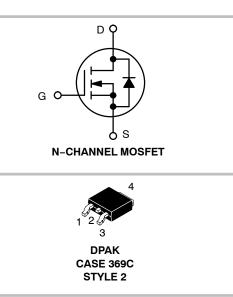
2. Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad. 3. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



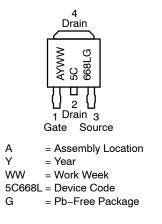
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V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub>	I <sub>D</sub>
60 V	8.9 mΩ @ 10 V	49 A
	12.8 mΩ @ 4.5 V	49 A



#### MARKING DIAGRAM **& PIN ASSIGNMENT**



#### **ORDERING INFORMATION**

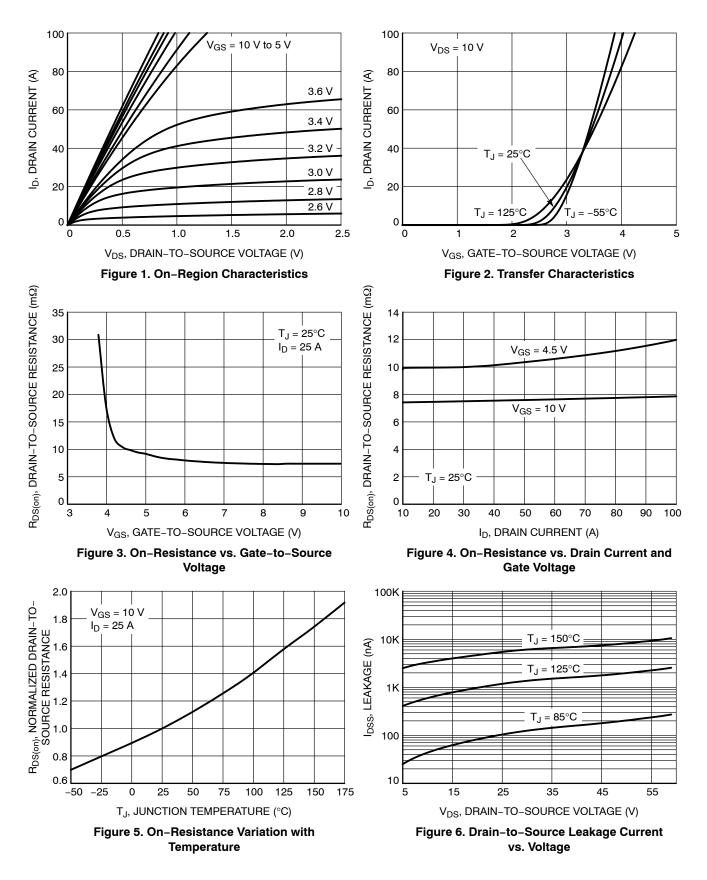
See detailed ordering and shipping information in the package dimensions section on page 5 of this data sheet.

## **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise noted)

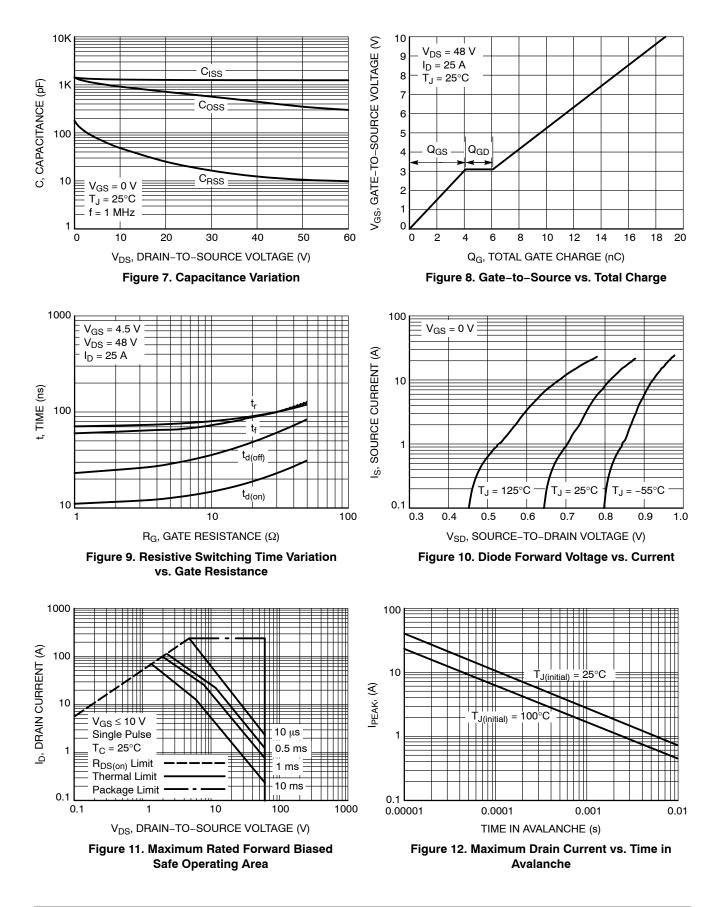
Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS					•	•	
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> =	= 250 μA	60			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /T <sub>J</sub>				27		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25°C			10	μΑ
		$V_{DS} = 60 V$	T <sub>J</sub> = 125°C			250	
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 V, V_{G}$	<sub>S</sub> = 20 V			100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D$	= 50 μA	1.2		2.1	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				4.8		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V, I <sub>E</sub>	<sub>0</sub> = 25 A		7.4	8.9	mΩ
		V <sub>GS</sub> = 4.5 V, I <sub>I</sub>	<sub>D</sub> = 25 A		10.2	12.8	
Forward Transconductance	9 <sub>FS</sub>	V <sub>DS</sub> = 15 V, I <sub>E</sub>	<sub>0</sub> = 25 A		60		S
CHARGES, CAPACITANCES AND GATE RE	SISTANCES				-		
Input Capacitance	C <sub>iss</sub>				1300		pF
Output Capacitance	C <sub>oss</sub>	$V_{GS}$ = 0 V, f = 1.0 MHz, $V_{DS}$ = 25 V			580		
Reverse Transfer Capacitance	C <sub>rss</sub>				18		
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>DS</sub> = 48 V,	V <sub>GS</sub> = 4.5 V		8.7		nC
			V <sub>GS</sub> = 10 V		18.7		
Threshold Gate Charge	Q <sub>G(TH)</sub>		1		2.4		nC
Gate-to-Source Charge	Q <sub>GS</sub>	V <sub>GS</sub> = 4.5 V, V <sub>E</sub>	- 48 V		4.1		
Gate-to-Drain Charge	Q <sub>GD</sub>	I <sub>D</sub> = 25	A		2.0		
Plateau Voltage	V <sub>GP</sub>				3.1		V
SWITCHING CHARACTERISTICS (Note 5)							
Turn-On Delay Time	t <sub>d(on)</sub>				12		ns
Rise Time	t <sub>r</sub>	Voo - 45 V Vr	- 48 V		74		1
Turn-Off Delay Time	t <sub>d(off)</sub>	$\begin{array}{l} V_{\mathrm{GS}} = 4.5 \; V, \; V_{\mathrm{DS}} = 48 \; V, \\ I_{\mathrm{D}} = 25 \; A, \; R_{\mathrm{G}} = 2.5 \; \Omega \end{array}$			26		
Fall Time	t <sub>f</sub>				62		
DRAIN-SOURCE DIODE CHARACTERISTIC							
Forward Diode Voltage			T,J = 25°C		0.87	1.2	V
	00	$v_{GS} = 0 v$ ,	T <sub>J</sub> = 125°C		0.76		1
Reverse Recovery Time	t <sub>RR</sub>		l °		32		ns
Charge Time	ta	V <sub>GS</sub> = 0 V, dls/dt = 100 A/µs, I <sub>S</sub> = 25 A			15		1
Discharge Time	tb				16		1
Reverse Recovery Charge	Q <sub>RR</sub>				20		nC

Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.
Switching characteristics are independent of operating junction temperatures.

#### **TYPICAL CHARACTERISTICS**



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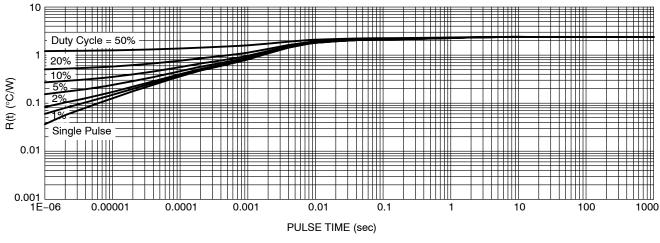


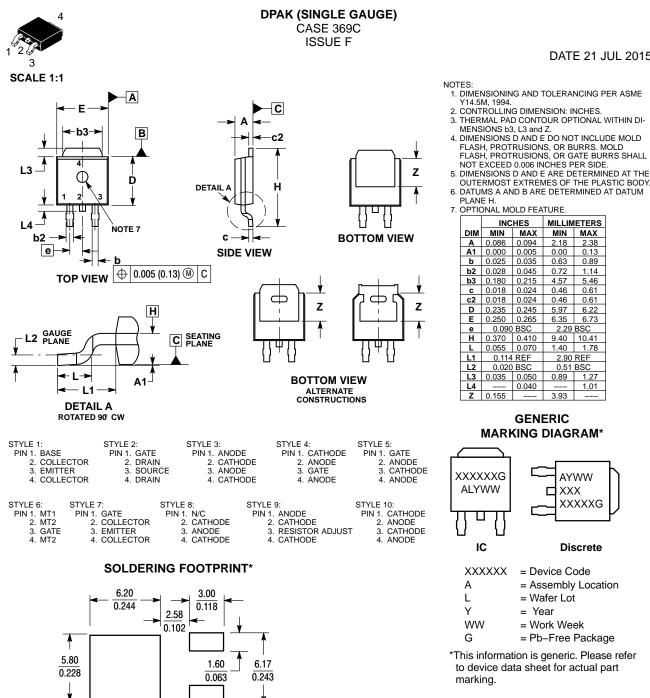
Figure 13. Thermal Response

#### **ORDERING INFORMATION**

Order Number	Package	Shipping <sup>†</sup>
NVD5C668NLT4G	DPAK (Pb–Free)	2500 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.





\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

DOCUMENT NUMBER:	98AON10527D	Electronic versions are uncontrolle	nent Repository. Printed	
STATUS:	ON SEMICONDUCTOR STANDARD	accessed directly from the Document versions are uncontrolled except		
NEW STANDARD:	REF TO JEDEC TO-252	"CONTROLLED COPY" in red.		
DESCRIPTION:	DPAK SINGLE GAUGE SURFACE MOUNT		PAGE 1 OF 2	

 $\left(\frac{\text{mm}}{\text{inches}}\right)$ 

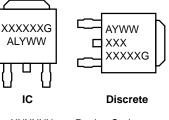
SCALE 3:1

#### DATE 21 JUL 2015

- 3. THERMAL PAD CONTOUR OPTIONAL WITHIN DI-MENSIONS b3, L3 and Z. 4. DIMENSIONS D AND E DO NOT INCLUDE MOLD
- FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL
- NOT EXCEED 0.006 INCHES PER SIDE. 5. DIMENSIONS D AND E ARE DETERMINED AT THE

OPTIONAL MOLD FEATURE.					
	INCHES		MILLIN	ETERS	
DIM	MIN	MAX	MIN	MAX	
Α	0.086	0.094	2.18	2.38	
A1	0.000	0.005	0.00	0.13	
b	0.025	0.035	0.63	0.89	
b2	0.028	0.045	0.72	1.14	
b3	0.180	0.215	4.57	5.46	
С	0.018	0.024	0.46	0.61	
c2	0.018	0.024	0.46	0.61	
D	0.235	0.245	5.97	6.22	
Е	0.250	0.265	6.35	6.73	
е	0.090	BSC	2.29 BSC		
н	0.370	0.410	9.40	10.41	
L	0.055	0.070	1.40	1.78	
L1	0.114	0.114 REF		REF	
L2	0.020 BSC		0.51	BSC	
L3	0.035	0.050	0.89	1.27	
L4		0.040		1.01	
Z	0.155		3.93		

# **MARKING DIAGRAM\***



XXXXXX	= Device Code
A	= Assembly Location
L	= Wafer Lot
Y	= Year
WW	= Work Week
G	= Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part





PAGE 2 OF 2

ISSUE	REVISION	DATE
0	RELEASED FOR PRODUCTION. REQ. BY L. GAN	24 SEP 2001
А	ADDED STYLE 8. REQ. BY S. ALLEN.	06 AUG 2008
В	ADDED STYLE 9. REQ. BY D. WARNER.	16 JAN 2009
С	ADDED STYLE 10. REQ. BY S. ALLEN.	09 JUN 2009
D	RELABELED DRAWING TO JEDEC STANDARDS. ADDED SIDE VIEW DETAIL A. CORRECTED MARKING INFORMATION. REQ. BY D. TRUHITTE.	29 JUN 2010
E	ADDED ALTERNATE CONSTRUCTION BOTTOM VIEW. MODIFIED DIMENSIONS b2 AND L1. CORRECTED MARKING DIAGRAM FOR DISCRETE. REQ. BY I. CAM-BALIZA.	06 FEB 2014
F	ADDED SECOND ALTERNATE CONSTRUCTION BOTTOM VIEW. REQ. BY K. MUSTAFA.	21 JUL 2015

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